## UCLA Samueli School of Engineering



# Phases Control on Epitaxial MnTe through Buffer Layers

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### Introduction

MnTe is one of the 3D semiconductors that can exhibit anomalous Hall effect. The potential edge states correlated with the alter-magnet properties in the  $\alpha$ -phase MnTe is also under study these days. The epitaxial growth becomes one method to tune the electronic structure. In this work we have grown both  $\alpha$ -phase and  $\beta$ -phase MnTe by Molecular Beam Epitaxy on GaAs (111) and sapphire (0001) substrates with different buffer layers. Meanwhile, both thin film and nanorod MnTe single crystals are grown.

## 1. By simply replacing Bi<sub>2</sub>Te<sub>3</sub> buffer by Bi<sub>2</sub>Se<sub>3</sub> we can control different phases of MnTe

β-MnTe	a-MnTe
Bi <sub>2</sub> Te <sub>3</sub>	Bl <sub>2</sub> Se <sub>3</sub>
sapphire (0001)	sapphire (0001)

Lattice constant from buffer layers influences MnTe phases, and can be used to grow the energy unfavorable one (in bulk) in the form of thin film.





This shows the influence not only from lattice constant in case 1, but also from entropy effect, remote potential, or surface energy.



Atomic Force Microscope (AFM) and phases of MnTe samples grown on different buffers and substrates





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## Result 1:



#### Result 2:

Phases control by changing buffer layer 1)  $\alpha$ -phase MnTe is grown on Bi<sub>2</sub>Se<sub>3</sub> /sapphire  $\beta$ -phase MnTe is grown on Bi<sub>2</sub>Te<sub>3</sub>/sapphire

2) α-phase MnTe is grown on (Bi,Sb)<sub>2</sub>Te<sub>3</sub>/GaAs β-phase MnTe is grown on Bi<sub>2</sub>Te<sub>3</sub>/GaAs

#### **Result 3:**

Single crystalline α-MnTe nano-rods are grown: potential advantages in measuring MnTe edge states





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